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Substitute for form 1449A/PTO				Complete if Known					
				Application Number	09/529,948	E	·		
IN	NFORMATIC	DN DI	SCLOSURE	Filing Date	April 21, 2000	10,	272	-7:	
S	TATEMENT	ΓBY /	APPLICANT	First Named Inventor	Sergey E. Yakove	enko	3		
				Art Unit	2871	J 7	<u> </u>	H	
	(use as many sheets as necessary)			Examiner Name	J. Dudek	177	2		
Sheet	1	of	2	Attorney Docket Number	8733.177.00-US	ΕŖ	£003	S	
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Examiner Initials*	Cite	Document Number Number-Kind Code ² (if known)	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant	
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		OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS	
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